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# **Pattern Recognition and Machine Learning Applications**

Guest Editors:

**Message from the Guest Editors** 

Prof. Dr. Junhui Zhao

Dear Colleagues,

Prof. Dr. Lisheng Fan

Dear concagaes,

Dr. Shengrong Bu

This topic is aimed at providing an interdisciplinary discussion to share the recent advancements in different areas of pattern recognition and artificial intelligence, with an emphasis on new approaches and techniques for machine-learning applications.

Deadline for manuscript submissions:

Topics of interest include (but are not limited to) the following:

closed (15 August 2023)

- Statistical and structural pattern recognition methods and applications;
- Signal and image processing;
- Computer vision and pattern recognition;
- Data analytics, data mining, and computing in big data;
- Machine-learning algorithm, model selection, clustering, and classification;
- Methodologies, frameworks, and models for pattern recognition;
- Machine-learning applications:
  - communications (such as V2X, IoT, MEC);
  - information processing;
  - o biometrics analysis;
  - healthcare and medical image analysis;
  - o natural language processing;
  - o scenario fusion and classification.











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### **Editor-in-Chief**

#### Prof. Dr. Flavio Canavero

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## **Message from the Editor-in-Chief**

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